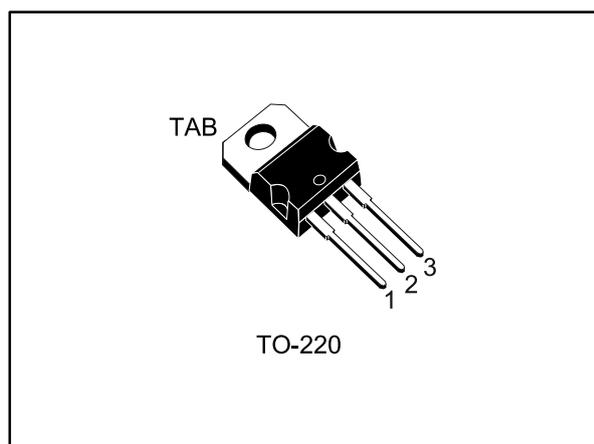


## N-channel 60 V, 0.0021 $\Omega$ typ., 120 A, STripFET™ F7 Power MOSFET in a TO-220 package

Datasheet - production data



### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)max</sub>	I <sub>D</sub>	P <sub>TOT</sub>
STP220N6F7	60 V	0.0024 $\Omega$	120 A	237 W

- Among the lowest R<sub>DS(on)</sub> on the market
- Excellent figure of merit (FoM)
- Low C<sub>rss</sub>/C<sub>iss</sub> ratio for EMI immunity
- High avalanche ruggedness

### Applications

- Switching applications

### Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Figure 1: Internal schematic diagram

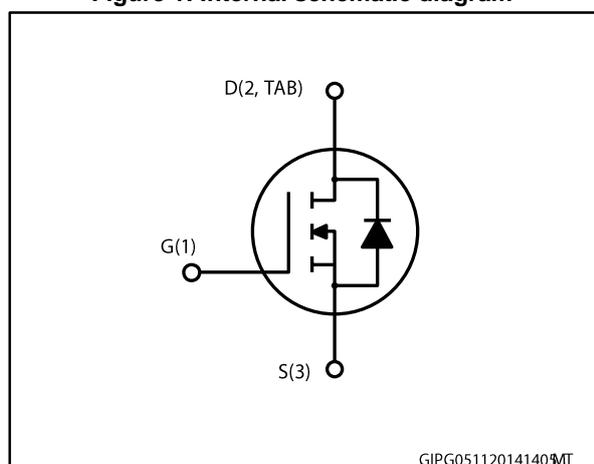


Table 1: Device summary

Order code	Marking	Package	Packaging
STP220N6F7	220N6F7	TO-220	Tube

# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	60	V
$V_{GS}$	Gate-source voltage	$\pm 20$	V
$I_D^{(1)}$	Drain current (continuous)	120	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	120	A
$I_{DM}^{(2)}$	Drain current (pulsed) $T_C = 25\text{ }^\circ\text{C}$	480	A
$P_{TOT}$	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	237	W
$E_{AS}^{(3)}$	Single pulse avalanche energy	1	J
$T_J$	Operating junction temperature	-55 to 175	$^\circ\text{C}$
$T_{stg}$	Storage temperature		$^\circ\text{C}$

**Notes:**

(1) Current limited by package

(2) Pulse width is limited by safe operating area

(3) Starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $I_d = 20\text{ A}$ ,  $V_{dd} = 50\text{ V}$

**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.63	$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	$^\circ\text{C/W}$

## 2 Electrical characteristics

( $T_C = 25\text{ °C}$  unless otherwise specified)

**Table 4: On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0, I_D = 1\text{ mA}$	60			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0, V_{DS} = 60\text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0, V_{DS} = 60\text{ V}, T_C = 125\text{ °C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0, V_{GS} = +20\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	2		4	V
$R_{DS(on)}$	Static drain-source on- resistance	$V_{GS} = 10\text{ V}, I_D = 60\text{ A}$		0.002 1	0.002 4	$\Omega$

**Table 5: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{GS} = 0, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$	-	6400	-	pF
$C_{oss}$	Output capacitance		-	3880	-	pF
$C_{rss}$	Reverse transfer capacitance		-	175	-	pF
$Q_g$	Total gate charge	$V_{DD} = 30\text{ V}, I_D = 120\text{ A}, V_{GS} = 10\text{ V}$	-	100	-	nC
$Q_{gs}$	Gate-source charge		-	36	-	nC
$Q_{gd}$	Gate-drain charge		-	24	-	nC

**Table 6: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30\text{ V}, I_D = 60\text{ A}, R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$	-	33	-	ns
$t_r$	Rise time		-	103	-	ns
$t_{d(off)}$	Turn-off delay time		-	54	-	ns
$t_f$	Fall time		-	29	-	ns

Table 7: Source drain diode

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
$V_{SD}^{(1)}$	Forward on voltage	$V_{GS} = 0, I_{SD} = 120 \text{ A}$	-	-	1.1	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 120 \text{ A},$ $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 48 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$	-	69		ns
$Q_{rr}$	Reverse recovery charge		-	104		nC
$I_{RRM}$	Reverse recovery current		-	3		A

**Notes:**

<sup>(1)</sup>Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%